

### CMOS-6/6A/6V/6X 1.0-MICRON CMOS GATE ARRAYS

**April 1992** 

### Description

NEC's CMOS-6 gate array families (CMOS-6, CMOS-6A, CMOS-6V and CMOS-6X) are ultra-high performance, sub-micron effective channel length CMOS products created for high-integration ASIC applications.

The device processing includes 1.0-micron (drawn) silicon-gate CMOS technology and three-layer (CMOS-6) and two-layer (CMOS-6A, CMOS-6V, CMOS-6V) metallization. This technology features channelless (sea-of-gates) architecture in densities from 1,200 to 177,408 equivalent gates, with an internal gate delay of 270 ps (F/O=1; L = 0). Output drive is variable to 18 mA. Slew rate buffers are also available.

CMOS-6 products are fully supported by NEC's advanced ASIC design technology. NEC's OpenCAD® integration system lets the designer choose the most powerful design tools and services available. The CMOS-6/6A/6V macro cell (block) library is compatible with the powerful CMOS-5 block library, which contain over 300 cells and more than 100 interface options.

NEC offers advanced packaging solutions with both through-hole and surface-mount ceramic PGAs and flat packages. These heat-sink-equipped packages give CMOS-6 devices the performance edge in high-integration applications.

### **Features**

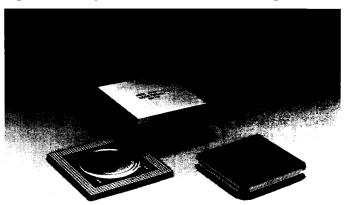
- □ Channelless, 1.µm CMOS high-density architecture
- □ Variable output drive: 4.5, 9.0, 13.5, or 18.0 mA
- Slew rate output buffers
- = Free size memory blocks to 64 Kbytes (16K x 4, μPD65676)
- □ Powerful block library with more than 400 macros
- 3V characterized block library
- New 0.65 mm 184-pin plastic QFP for cost effective designs
- □ High I/O to gate ratio for CMOS-6V and CMOS-6X

### **Publications**

This data sheet contains preliminary specifications, package information, and operational data for the CMOS-6 gate array families. Additional design information is available in NEC's CMOS-6 Block Library and CMOS-6 Design Manual. Contact your local NEC Design Center or the NEC Literature Center for further ASIC design information; see the back of this data sheet for locations and phone numbers.

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Figure 1. Sample CMOS-6/6A/6V/6X Packages



### **Gate Array Sizes**

		Estimate	d Usable Gates	
Device	Available	-	Design =	I/O Pads
(μ <b>PD</b> )	Gates	50% Memory	All Random*	(Max.)
CMOS-6	X Devices			
65612	1,200	1,000	800	64
65622	2,700	2,300	1,900	84
65626	3,900	3,300	2,700	104
65632	5,600	3,900	3,900	104
CMOS-6	A Devices			
65630	5,376	4,600	3,800	84
65636	8,000	6,800	5,600	100
65640	11,520	9,800	8,100	120
65646	16,240	13,800	11,400	140
65650	21,120	18,000	14,800	160
65654	30,720	26,100	21,500	192
CMOS-6	V Devices			
65631	5,544	4,700	3,900	140
65641	11,520	9,800	8,100	160
65644	14,040	11,900	9,800	160
65647	16,240	13,800	11,400	160
65648	18,600	15,800	13,000	160
65651	21,120	18,000	14,800	220
65652	26,640	22,600	18,600	220
65655	30,720	26,100	21,500	<b>,</b> 220
CMOS-6	Devices			
65658	42,240	37,000	21,700	220
65664	72,576	63,500	54,400	288
65672	119,232	104,300	89,400	368
65676	177,408	155,200	133,100	448

Actual gate utilitization may vary depending on circuit implementation.

Utilization is 75% for three-layer metal; 70% for two-layer metal.

Memory utilization is determined by 50% x available gates + (utilization x 50% available gates)

Depending on package and circuit specification, some pads are used for  $\rm V_{DD}$  and GND and are unavailable as signal pads.



### **Circuit Architecture**

CMOS-6 products are built with NEC's 1-micron channelless architecture. As shown in figure 2, CMOS gate array chips are divided into I/O and internal cell areas. The I/O cell area contains input and output buffers that isolate the internal cells from high-energy external signals. The internal cell area is an array of basic cells, each composed of two p-channel MOS transistors and two n-channel MOS transistors, as well as four additional n-channel MOS transistors for compact RAM design. A cell configured as a two-input NAND gate is shown in figure 3. These p-channel and n-channel transistors are sized to offer a superb ratio of speed to silicon area.

Figure 2. Chip Layout and Internal Cell Configuration

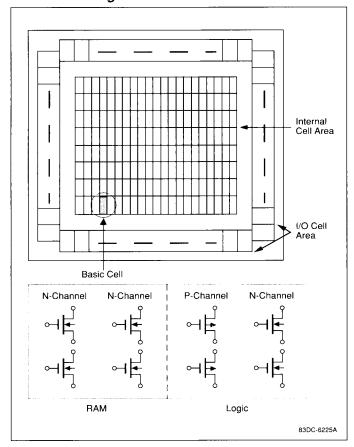
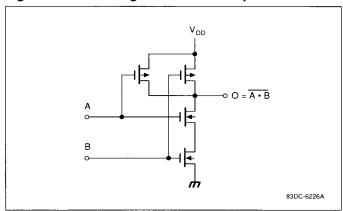


Figure 3. Cell Configured as a Two-Input NAND



### **Output Slew Rate Selection**

Fast rise and fall times of CMOS output buffers can cause system noise and signal overshoot. When an unterminated line is being driven by a buffer, the maximum line length is determined by the rise and fall time of the output buffers and the round-trip signal delay of the line.

As a general rule, the round-trip delay of the line should not exceed the rise or fall time of the driving signal. Transmission lines that are longer than those determined by the above rule can cause system performance degradation because of reflections and ringing. One benefit of slew rate output buffers is that longer interconnections on a PC board (and routing flexibility) are possible with slew rate output buffers.

The ASIC designer can slow down the output edge rate by selecting the slew rate output buffer and thus allowing for a longer line.

Also, as the slew rate buffers inject less noise than their non-slew rate counterparts into the internal power and ground busses of the devices, the slew rate buffers require fewer power pairs for simultaneous switching outputs.



### **Absolute Maximum Ratings**

Power supply voltage, V <sub>DD</sub>	-0.5 to +6.5 V
Input/output voltage, V <sub>I</sub> / V <sub>O</sub>	-0.5 V to V <sub>DD</sub> + 0.5 V
Latch-up current, I <sub>LATCH</sub>	>1 A (typ)
Output current, I <sub>O</sub>	
4.5-mA drive	10 mA
9-mA drive	20 mA
13.5-mA drive	30 mA
18-mA drive	40 mA
Operating temperature, T <sub>OPT</sub>	−40 to +85°C
Storage temperature, T <sub>STG</sub>	−65 to +150°C

Caution: Exposure to absolute maximum ratings for extended periods may affect device reliability; exceeding the ratings could cause permanent damage. The device should not be operated outside the recommended operating conditions.

# Input/Output Capacitance $V_{DD} = V_i = 0 \ V; f = 1 \ MHz$

Terminal	Symbol	Тур	Max	Unit
Input	C <sub>IN</sub>	10	25	pF
Output	C <sub>OUT</sub>	10	25	pF
I/O	C <sub>I/O</sub>	10	25	рF

### Note:

(1) Values include package pin capacitance.

### **Power Consumption**

Description	Limits (max)	Unit	<b>Test Conditions</b>
Internal cell	8	μW/MHz	F/O = 3; L = 3 mm
Input block	46	μW/MHz	F/O = 3; L = 3 mm
Output block	.98	mW/MHz	C <sub>L</sub> = 15 pF

### **Recommended Operating Conditions**

		CMOS	Level	ΠL		
Parameter	Symbol	Min	Max	Min	Max	Unit
Power supply voltage	V <sub>DD</sub>	4.5	5.5	4.75	5.25	٧
Ambient temperature	T <sub>A</sub>	-40	+85	0	+70	°C
Low-level input voltage	V <sub>IL</sub>	0	0.3 V <sub>DD</sub>	0	0.8	V
High-level input voltage	V <sub>IH</sub>	0.7 V <sub>DD</sub>	V <sub>DD</sub>	2.2	V <sub>DD</sub>	V
Input rise or fall time	t <sub>R</sub> , t <sub>F</sub>	0	200	0	200	ns
Input rise or fall time, Schmitt	t <sub>R</sub> , t <sub>F</sub>	0	10	0	10	ms
Positive Schmitt-trigger voltage	V <sub>P</sub>	1.8	4.0	1.2	2.4	V
Negative Schmitt-trigger voltage	V <sub>N</sub>	0.6	3.1	0.6	1.8	V
Hysteresis voltage	V <sub>H</sub>	0.3	1.5	0.3	1.5	٧

### **AC Characteristics**

 $V_{DD} = 5 \text{ V} \pm 10\%; \ \text{T}_{A} = -40 \text{ to } +85^{\circ}\text{C}$ 

Parameter	Symbol	Min	Тур	Max	Unit	Conditions
Toggle frequency	f <sub>TOG</sub>	120			MHz	D-F/F; F/O = 2
Delay time, internal gate	t <sub>PD</sub>		270		ps	F/O = 1; L = 0 mm
Delay time, 2-input NAND gate			700		ps	F/O = 3; L = 3 mm
Delay time, buffer						
Input (FI01)	t <sub>PD</sub>		1.25		ns	F/O = 3; L = 3 mm
Output (FO01)	t <sub>PD</sub>		2.0		ns	C <sub>L</sub> = 15 pF
Output rise time	t <sub>R</sub>		3.0		ns	C <sub>L</sub> = 15 pF
Output fall time	t <sub>E</sub>		2.0		ns	C <sub>1</sub> = 15 pF

### **CMOS-6/6A/6V/6X**



### **DC Characteristics**

 $V_{DD} = 5 \text{ V} \pm 10\%$ ;  $T_{A} = -40 \text{ to } +85 \text{ }^{\circ}\text{C}$ 

Parameter	Symbol	Min	Тур	Max	Unit	Conditions
Quiescent current (Note 1)	IL		0.1	400	μА	$V_1 = V_{DD}$ or GND
Input leakage current					-	
Regular	I <sub>I</sub>		10 <sup>-5</sup>	10	μΑ	$V_{l} = V_{DD}$ or GND
50 kΩ pull-up	1,	-40	-100	-270	μΑ	V <sub>I</sub> = GND
5 kΩ pull-up	1,	-0.35	-1.0	-2.2	mA	V <sub>I</sub> = GND
50 kΩ pull-down	l <sub>i</sub>	45	120	300	μΑ	$V_I = V_{DD}$
Off-state output leakage current	l <sub>oz</sub>			10	μА	V <sub>O</sub> = V <sub>DD</sub> or GND
Input clamp voltage	V <sub>IC</sub>	-1.2			V	I <sub>I</sub> = 18 mA
Output short circuit current (Note 2)	los	-250			mA	V <sub>O</sub> = 0 V
Low-level output current (CMOS)						
4.5 mA (Note 3)	l <sub>oL</sub>	4.5			mA	V <sub>OL</sub> = 0.4 V
9 mA (Note 3)	l <sub>OL</sub>	9.0			mA	V <sub>OL</sub> = 0.4 V
13.5 mA (Note 3)	l <sub>oL</sub>	13.5			mA	V <sub>OL</sub> = 0.4 V
18 mA (Note 3)	l <sub>oL</sub>	18.0			mA	V <sub>OL</sub> = 0.4 V
High-level output current (CMOS)						
4.5 mA (Note 3)	Гон	-2.5			mA	$V_{OH} = V_{DD} - 0.4 V$
9 mA (Note 3)	Гон	-5.0			mA	$V_{OH} = V_{DD} - 0.4 V$
13.5 mA (Note 3)	Гон	-7.5			mA	$V_{OH} = V_{DD} - 0.4 V$
18 mA (Note 3)	Гон	-10.0			mA	$V_{OH} = V_{DD} - 0.4 V$
Low-level output current (TTL)						
9 mA (Note 4)	l <sub>OL</sub>	9.0			mA	V <sub>OL</sub> = 0.4 V
18 mA (Note 4)	l <sub>oL</sub>	18.0			mA	V <sub>OL</sub> = 0.4 V
High-level output current (TTL)						
9 mA (Note 4)	I <sub>OH</sub>	-0.5			mA	V <sub>OH</sub> = 2.4 V
18 mA (Note 4)	Гон	-1.0			mA	V <sub>OH</sub> = 2.4 V
Low-level output voltage	V <sub>OL</sub>			0.1	V	I <sub>OL</sub> = 0 mA
High-level output voltage (CMOS) (Note 3)	V <sub>OH</sub>	V <sub>DD</sub> -0.1			٧	I <sub>OH</sub> = 0 mA
High-level output voltage (TTL) (Note 4)	V <sub>OH</sub>	2.6	3.4		٧	I <sub>OH</sub> = 0 mA

<sup>(1)</sup> The maximum value reflects the use of pull-up/pull-down resistors and oscillator blocks. Contact an NEC ASIC Design Center for assistance in calculation.

 $<sup>\</sup>begin{tabular}{ll} (2) & Rating is for only one output operating in this mode for less than 1 second. \\ \end{tabular}$ 

<sup>(3)</sup> CMOS-level output buffer ( $V_{DD}$  = 5 V  $\pm$  10%,  $T_{A}$ = -40 to +85°C). (4) TTL-level output buffer ( $V_{DD}$  = 5 V  $\pm$  5%,  $T_{A}$ = 0 to +70°C).



Pa	ıçl	ka	q	е	Ρ	la	n
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		CMO					MO PD6								S-6\ 65xx				}		OS-( 65x)	
	612	622	626	632	630	636	640	646	650	654	631	641	644	647	648	651	652	655	658	664	672	676
K gates (usable w/o memory)	0.8	1.9	2.7	3.9	3.8	5.6	8.1	11.4	1 14.8	21.5	3.9	8.1	9.8	11.4	13.0	14.8	18.6	21.5	21.7	54.4	89.4	133
Maximum I/O Pins	64	84	104	104	84	100	120	140	160	192	140	160	160	160	160	220	220	220	220	288	368	448
Plastic Quad Flatpack (QFP)																						
44-pin	Α	Α	Α		Α	Α	Α	Α	Α													
52-pin	Α	Α	Α		Α	Α	Α	Α	Α	Α												
64-pin		Α	Α		Α	Α	Α	Α	Α	Α												
80-pin			Α		Α	Α	Α	Α	$A^1$	Α												
100-pin						Α	Α	Α	Α	Α	Α								Α			
120-pin							Α	Α	Α	Α	Α								Α	Α	Α	
136-pin								Α	Α	Α	Α	Α	Α						Α	Α	Α	
160-pin									Α	Α	Ε	Α	Α	Α	Α				Α	Α	Α	Α
184-pin										Α						Α	Α		Α	Α	Α	Α
Thin Quad Flatpack (TQFP)																						
80-pin			Α																			
Shrink Plastic Quad Flatpack (QFI	P-FP) (	.5 m	m L	ead Pi	tch)																	
100-pin						Α	Α	Α	Α	Α	Α								Α			
120-pin							Α	Α	Α	Α	Α								Α	Α	Α	
136-pin								Α	Α	Α	Α											
144-pin											Ε	Α	Α						Α	Α	Α	
160-pin*									Α	Α		Α	Α	Α	Α				Α	Α	Α	Α
176-pin									Â	A		Â	A	A	A	Α	Α		A	A	A	A
208-pin*									,,	, ,		,,	, ,	, ,	, ,	A	A	Α	A	A	A	Α
304-pin																<i></i>	,,	^\	, ,	Ë	E	E
Ceramic Pin Grid Array (PGA)																						
72-pin							Α	A	Α	Α												
132-pin								Α	Α	Α	Α	Α							Α	Α	Α	Α
176-pin										Α						Α	Α		Α	Α	Α	Α
208-pin																			Α	Α	Α	Α
																				Α	Α	Α
280-pin 364-pin																				^	Â	Ā
Ceramic Pin Grid Array (PGA) (Bu	ıtt Lead	)																				
288-pin			•																		A <sup>1</sup>	A <sup>1</sup>
528-pin (with heat sink)																						Α
528-pin (without heat sink)																						Α
Plastic Leaded Chip Carrier (PLCC	<b>C</b> )																					
68-pin																			A			
84-pin																			Α			
Δ - Δvailable																						

A = Available

**NOTE:** NEC reserves the right to alter the package plan based on the results of qualification. For current package availability, please contact your local NEC Design Center.

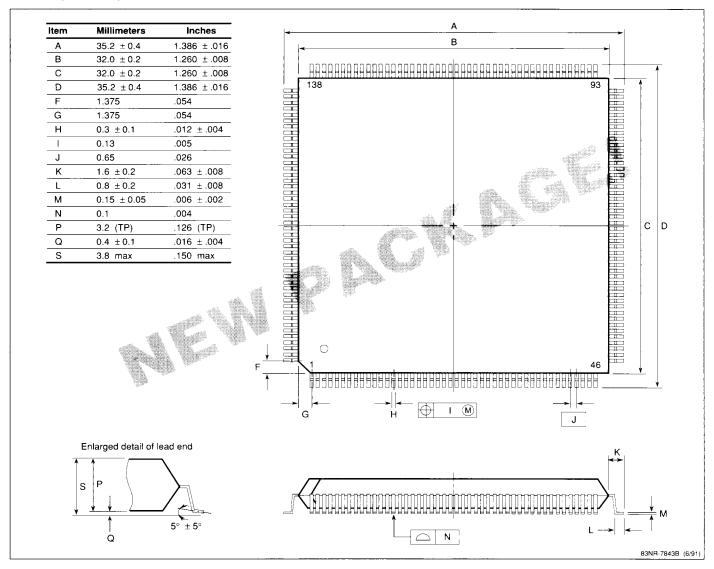
A<sup>1</sup>= Need advanced notice

E = Under Evaluation

<sup>\* =</sup> Heat spreader under evaluation

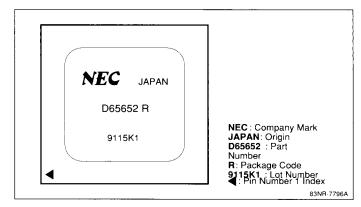


184-Pin (0.65 mm) Plastic QFP



The new 184-pin 0.65 mm QFP shown above is ideal for PC integrated chipsets. The package is available with a copper leadframe thereby allowing greater heat dissipation than standard 42 alloy leadframe packages. The 0.65 mm pin pitch allows the use of widely available, cost effective assembly equipment. It is currently available in two masterslices. The  $\mu\text{PD65658}$  with 25,344 usable gates and the  $\mu\text{PD65664}$  with 43,545 usable gates.

### Typical Package Marking





### **NEC's ASIC Design System**

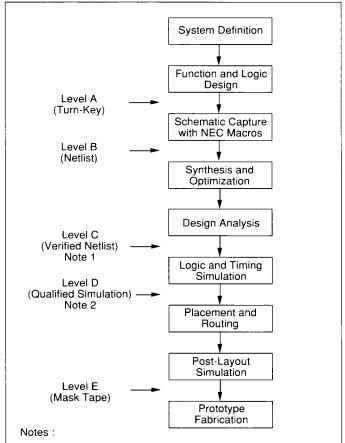
CMOS-6/6A/6V gate arrays are fully supported by NEC's network of ASIC Design Centers, listed on the back of this data sheet.

Design flow for CMOS-6/6A/6V gate arrays is shown in figure 4. Users can enlist Design Center support at any step in the design flow before actual manufacturing. Figure 4 shows the various levels at which Design Center support may begin — anywhere from level A through level E. Level C, "Verified Netlist," is the most popular interface.

NEC supports its ASIC products with a comprehensive CAD system that significantly reduces the time and expense usually associated with the development of semicustom devices. NEC's OpenCAD integration system supports tools for floorplanning, logic synthesis, automatic test generation, accelerated fault grading and full timing simulation, and advanced place-and-route algorithms. These advanced CAD tools ensure accurate designs.

Sample design kits are available at no charge to qualified users: contact an NEC ASIC Design Center for more information. (Software licensing required—NEC reserves the right to prioritize support based on user requirements.)

Figure 4. Gate Array Design Flow



- (1) NEC supports the most popular workstations, including Mentor Graphics, Valid, DAZIX®, FutureNet, Viewlogic®, and HP9000 workstations, for the NEC ASIC product line. However, NEC does not support all workstations for all products. Please contact your nearest NEC ASIC Design Center for more information.
- (2) NEC provides support of System HILO®, Verilog®, and MACH 1000/1500™ interface capability.

DAZIX is a registered trademark of DAZIX Daisy / Cadnetix Inc. Viewlogic is a registered trademark of Viewlogic Systems, Inc. System HILO is a registered trademark of GenRad. Verilog is a registered trademark of Cadence Design Systems, Inc. MACH 1000 and MACH 1500 are trademarks of Zycad Corp.

### **CMOS-6/6A/6V/6X**



18.0

18.0

Cells

1 (6)

1 (6)

1 (5)

1 (5)

Description

### **Block Library List**

The CMOS-6 families offer a variety of blocks, including gates, flip-flop circuits, and shift registers. The functions of these blocks are designed to be compatible with those of the CMOS-4 and CMOS-5 families.

In addition, such memory blocks as RAM and ROM and low-power gates are provided. The low-power block, in particular, was designed with low fan-out taken into consideration; the number of cells is less than that of the standard block, contributing to low power consumption and high efficiency.

conci	deration; the number of cells is less than	that a	of the		30 K22 pull-down res.		
stand	ard block, contributing to low power co igh efficiency.			BOUE BOWE BT08 BTU8	Output buffer, CMOS 3-state out, 50 k $\Omega$ pull-up resolutput buffer, CMOS 3-state out, 5 k $\Omega$ pull-up resolutput buffer, TTL 3-state out Output buffer, TTL 3-state out, 50 k $\Omega$ pull-up res.		1 (5) 1 (5) 1 (6) 1 (6)
Bloc	k List			BTW8	Output buffer, TTL 3-state out, 50 kΩ pull-up res.	9.0	1 (6)
Block Name	Description		Cells	BT09 BTU9 BTW9	Output buffer, TTL 3-state out, 50 k $\Omega$ pull-up res. Output buffer, TTL 3-state out, 50 k $\Omega$ pull-up res. Output buffer, TTL 3-state out, 50 k $\Omega$ pull-up res.	18.0 18.0	2 (12) 2 (12) 2 (12)
	Interface Blocks			EXT1	Output buffer, N-ch open drain	9.0	1 (2)
Inputs	laced by Kar OMOC is		1 (3)	EXT3 EXW3 EXT2	Output buffer, N-ch open drain, 50 k $\Omega$ pull-up res.	9.0 9.0 *9.0	1 (2) 1 (2) 1 (2)
FI01 FID1 FIU1 FIW1	Input buffer, CMOS in Input buffer, CMOS in, 50 k $\Omega$ pull-down res. Input buffer, CMOS in, 50 k $\Omega$ pull-up res. Input buffer, CMOS in, 5 k $\Omega$ pull-up res.	-	1 (3) 1 (3) 1 (3)	EXT4 EXT5 EXT7	Output buffer, P-ch open drain, 50 k $\Omega$ pull-up res. Output buffer, N-ch open drain Output buffer, N-ch open drain, 50 k $\Omega$ pull-up res.	*9.0 18.0 18.0	1 (2) 1 (2) 1 (2)
FI02 FID2 FIU2 FIW2	Input buffer, TTL in Input buffer, TTL in, 50 k $\Omega$ pull-down res. Input buffer, TTL in, 50 k $\Omega$ pull-up res. Input buffer, TTL in, 5 k $\Omega$ pull-up res.	- - -	1 (3) 1 (3) 1 (3) 1 (3)	EXW7 EXT6 EXT8	Output buffer, N-ch open drain, $5 \text{ k}\Omega$ pull-up res. Output buffer, P-ch open drain, $50 \text{ k}\Omega$ pull-up res. Output buffer, P-ch open drain, $50 \text{ k}\Omega$ pull-down res.	18.0 *18.0 *18.0	1 (2) 1 (2) 1 (2)
FIB1 FIB2 FDS1	Input buffer, CMOS in, high fanout for clock driver Input buffer, TTL in, high fanout for clock driver Input buffer, CMOS Schmitt in, 50 k $\Omega$ pull-down re	- - :S	1 (24) 1 (24) 1 (6)	EXT9 EXTB	Output buffer, N-ch open drain Output buffer, N-ch open drain, 50 k $\Omega$ pull-up res. Output buffer, N-ch open drain, 5 k $\Omega$ pull-up res.		1 (2) 1 (2) 1 (2)
FIS1	Input buffer, CMOS Schmitt in	-	1 (6)			13.3	1 (2)
FUS1 FWS1 FDS2 FIS2	Input buffer, CMOS Schmitt in, 50 k $\Omega$ pull-up res. Input buffer, CMOS Schmitt in, 5 k $\Omega$ pull-up res. Input buffer, TTL Schmitt in, 50 k $\Omega$ pull-down res. Input buffer, TTL Schmitt in	-	1 (6) 1 (6) 1 (6) 1 (6)	I/O Bu	cates I <sub>OH</sub> ffers  I/O buffer, CMOS in, CMOS 3-state out	13.5	1 (9)
FUS2 FWS2	Input buffer, TTL Schmitt in, 50 k $\Omega$ pull-up res. Input buffer, TTL Schmitt in, 5 k $\Omega$ pull-up res.	-	1 (6) 1 (6)	B0D1 B0U1	I/O buffer, CMOS in, CMOS 3-state out, 50 k $\Omega$ pull-down res. I/O buffer, CMOS in, CMOS 3-state out,	13.5 13.5	1 (9) 1 (9)
	•		•	2001	50 k $\Omega$ pull-up res.	70.0	. (0)
Output				B0W1		13.5	1 (9)
FO01	Output buffer, CMOS out	9.0	1 (2)		5 k $\Omega$ pull-up res.		
FO02 FO03 FO04	Output buffer, CMOS out Output buffer, CMOS out Output buffer, CMOS out	13.5 18.0 4.5	1 (4) 1 (4) 1 (2)	B002 B0D2	I/O buffer, TTL in, CMOS 3-state out I/O buffer, TTL in, CMOS 3-state out, 50 k $\Omega$ pull-down res.	13.5 13.5	1 (9) 1 (9)
FT01 FT02	Output buffer, TTL out Output buffer, TTL out	9.0 18.0	1 (4) 2 (6)	B0U2	I/O buffer, TTL in, CMOS 3-state out, 50 k $\Omega$ pull-up res.	13.5	1 (9)
B007 B0D7	Output buffer, CMOS 3-state out Output buffer, CMOS 3-state out,	13.5 13.5	1 (6) 1 (6)	B0W2	I/O buffer, TTL in, CMOS 3-state out, 5 k $\Omega$ pull-up res.	13.5	1 (9)
B0U7	50 kΩ pull-down res.  Output buffer, CMOS 3-state out,	13.5	1 (6)	B003 B0D3	I/O buffer, CMOS in, CMOS 3-state out I/O buffer, CMOS in, CMOS 3-state out,	9.0 9.0	1 (8) 1 (8)
B0W7	50 kΩ pull-up res. Output buffer, CMOS 3-state out, 5 kΩ pull-up res	. 13.5	1 (6)	B0U3	50 k $\Omega$ pull-down res. I/O buffer, CMOS in, CMOS 3-state out,	9.0	1 (8)
B008 B0D8	Output buffer, CMOS 3-state out Output buffer, CMOS 3-state out, $50 \text{ k}\Omega$ pull-down res.	9.0 9.0	1 (5) 1 (5)	B0W3	50 k $\Omega$ pull-up res. I/O buffer, CMOS in, CMOS 3-state out, 5 k $\Omega$ pull-up res.	9.0	1 (8)
B0U8	Output buffer, CMOS 3-state out, 50 kΩ pull-up re	s. 9.0	1 (5)	B004	I/O buffer, TTL in, CMOS 3-state out	9.0	1 (8)
B0W8	Output buffer, CMOS 3-state out, 5 k $\Omega$ pull-up res		1 (5)	B0D4	I/O buffer, TTL in, CMOS 3-state out,	9.0	1 (8)
B009 B0D9	Output buffer, CMOS 3-state out Output buffer, CMOS 3-state out,	18.0 18.0	1 (6) 1 (6)	B0U4	50 kΩ pull-down res. I/O buffer, TTL in, CMOS 3-state out,	9.0	1 (8)
	50 kΩ pull-down res.			B0W4	50 k $\Omega$ pull-up res. I/O buffer, TTL in, CMOS out, 5 k $\Omega$ pull-up res.	9.0	1 (8)

**Block** 

Name

B0W9

B00E

Outputs (Cont.)

B0U9 Output buffer, CMOS 3-state out,

B0DE Output buffer, CMOS 3-state out,

50 k $\Omega$  pull-down res.

Output buffer, CMOS 3-state out,

Output buffer, CMOS 3-state out

50 k $\Omega$  pull-up res.

 $5 \text{ k}\Omega$  pull-up res.

Note: Number of internal cells required is shown in parentheses.



Block Name	Description	l <sub>oL</sub> (mÅ)	Cells	Block Name	Description	I <sub>OL</sub> (mA)	Cells
	Interface Blocks (Cont.)				Interface Blocks (Cont.)		
I/O Buf	fers (Cont.)			I/O Buf	fers (Cont.)		
B005	I/O buffer, CMOS in, CMOS 3-state out	18.0	1 (9)	BSD4	I/O buffer, TTL Schmitt in, CMOS 3-state out,	9.0	1 (11)
B0D5	I/O buffer, CMOS in, CMOS 3-state out,	18.0	1 (9)	BSI4	50 k $\Omega$ pull-down res. I/O buffer, TTL Schmitt in, CMOS 3-state out	0.0	1 (11)
B0U5	50 kΩ pull-down res. I/O buffer, CMOS in, CMOS 3-state out,	18.0	1 (9)	BSU4			1 (11)
B0W5	50 k $\Omega$ pull-up res. I/O buffer, CMOS in, CMOS 3-state out, 5 k $\Omega$ pull-up res.	18.0	1 (9)	BSW4	• •	9.0	1 (11)
B006	I/O buffer, TTL in, CMOS 3-state out	18.0	1 (9)	BSD5	I/O buffer, CMOS Schmitt in, CMOS 3-state out,	18.0	1 (12)
B0D6	I/O buffer, TTL in, CMOS 3-state out,	18.0	1 (9)		50 k $\Omega$ pull-down res.	40.0	4 (40)
B0U6	50 k $\Omega$ pull-down res. I/O buffer, TTL in, CMOS 3-state out,	18.0	1 (9)	BSI5 BSU5			1 (12) 1 (12)
B0 <b>W</b> 6	50 k $\Omega$ pull-up res. I/O buffer, TTL in, CMOS 3-state out, 5 k $\Omega$ pull-up res.	18.0	1 (9)	BSW5	50 k $\Omega$ pull-up res. I/O buffer, CMOS Schmitt in, CMOS 3-state out, 5 k $\Omega$ pull-up res.	18.0	1 (12)
B00A	I/O buffer, TTL in, TTL 3-state out	9.0	1 (9)	BSD6	I/O buffer, TTL Schmitt in, CMOS 3-state out,	18.0	1 (12)
	I/O buffer, TTL in, TTL 3-state out,	9.0	1 (9)	BSI6	50 k $\Omega$ pull-down res. I/O buffer, TTL Schmitt in, CMOS 3-state out	18.0	1 (12)
B0WA	50 k $\Omega$ pull-up res. I/O buffer, TTL in, TTL 3-state out, 5 k $\Omega$ pull-up re	s. 9.0	1 (9)	BSU6	I/O buffer, TTL Schmitt in, CMOS 3-state out,		1 (12)
B00B	I/O buffer, TTL in, TTL 3-state out		2 (15)	DCMC	50 kΩ pull-up res.	100	1 (10)
B0UB	I/O buffer, TTL in, TTL 3-state out,	18.0	2 (15)	B2W6	I/O buffer, TTL Schmitt in, CMOS 3-state out, 5 k $\Omega$ pull-up res.	10.0	1 (12)
BOWB	50 k $\Omega$ pull-up res. I/O buffer, TTL in, TTL 3-state out, 5 k $\Omega$ pull-up re	s.18.0	2 (15)	BSIA	I/O buffer, TTL Schmitt in, TTL 3-state out		1 (12)
B00C	I/O buffer, CMOS in, CMOS 3-state out	4.5	1(8)	BSUA		9.0	1 (12)
B0DC	I/O buffer, CMOS in, CMOS 3-state out, 50 k $\Omega$ pull-down res.	4.5	1(8)	BSWA	50 kΩ pull-up res. I/O buffer, TTL Schmitt in, TTL 3-state out, 5 kΩ pull-up res.	9.0	1 (12)
B0UC	I/O buffer, CMOS in, CMOS 3-state out,	4.5	1 (8)	BSIB	I/O buffer, TTL Schmitt in, TTL 3-state out	18.0	2 (18)
B0WC	50 k $\Omega$ pull-up res. I/O buffer, CMOS in, CMOS 3-state out, 5 k $\Omega$ pull-up res.	4.5	1 (8)	BSUB	I/O buffer, TTL Schmitt in, TTL 3-state out, 50 k $\Omega$ pull-up res.	18.0	2 (18)
B00D B0DD	I/O buffer, TTL in, CMOS 3-state out I/O buffer, TTL in, CMOS 3-state out,	4.5 4.5	1 (8) 1 (8)	BSWB	I/O buffer, TTL Schmitt in, TTL 3-state out, 5 k $\Omega$ pull-up res.	18.0	2 (18)
	50 k $\Omega$ pull-down res.			BSDC	I/O buffer, CMOS Schmitt in, CMOS 3-state out,	4.5	1 (11)
B0UD	I/O buffer, TTL in, CMOS 3-state out, 50 k $\Omega$ pull-up res.	4.5	1 (8)	BSIC	50 k $\Omega$ pull-down res. I/O buffer, CMOS Schmitt in, CMOS 3-state out	4.5	1 (11)
B0WD	I/O buffer, TTL in, CMOS 3-state out, $6 \text{ k}\Omega$ pull-up res.	4.5	1 (8)	BSUC	I/O buffer, CMOS Schmitt in, CMOS 3-state out, 50 k $\Omega$ pull-up res.	4.5	1 (11)
BSD1	I/O buffer, CMOS Schmitt in, CMOS 3-state out, 50 k $\Omega$ pull-down res.		1 (12)	BSWC	I/O buffer, CMOS Schmitt in, CMOS 3-state out, $5 \text{ k}\Omega$ pull-up res.	4.5	1 (11
BSI1	I/O buffer, CMOS Schmitt in, CMOS 3-state out		1 (12)	BSDD	I/O buffer, TTL Schmitt in, CMOS 3-state out,	4.5	1 (11
BSU1	I/O buffer, CMOS Schmitt in, CMOS 3-state out, 50 k $\Omega$ pull-up res.	13.5	1 (12)	Bein	50 kΩ pull-down res.	4.5	1 /11
BSW1	I/O buffer, CMOS Schmitt in, CMOS 3-state out,	13.5	1 (12)	BSID	I/O buffer, TTL Schmitt in, CMOS 3-state out		1 (11
BSD2		13.5	1 (12)		I/O buffer, TTL Schmitt in, CMOS 3-state out, 50 k $\Omega$ pull-up res. I/O buffer, TTL Schmitt in, CMOS 3-state out,		1 (11
BSI2	50 k $\Omega$ pull-down res. I/O buffer, TTL Schmitt in, CMOS 3-state out	13.5	1 (12)		$5$ k $\Omega$ pull-up res.		,
	I/O buffer, TTL Schmitt in, CMOS 3-state out,		1 (12)	Slew F	Rate Output Buffers		
BSW2	50 kΩ pull-up res.  I/O buffer, TTL Schmitt in, CMOS 3-state out,	13.5	1 (12)	FE03 BE09	18 mA CMOS level slew rate output buffer 18 mA CMOS 3-state slew rate output buffer		1 (4 1 (5
BSD3	5 kΩ pull-up res. I/O buffer, CMOS Schmitt in, CMOS 3-state out, 50 kΩ pull-down res.	9.0	1 (11)	BED9	18 mA CMOS 3-state slew rate output buffer with 50K pull-down res.		1 (5
BSI3	I/O buffer, CMOS Schmitt in, CMOS 3-state out	9.0	1 (11)	BEU9			1 /5
BSU3	I/O buffer, CMOS Schmitt in, CMOS 3-state out,	9.0	1 (11)	BEMO	with 50K pull-up res.  18 mA CMOS 3-state slew rate output buffer		1 (5 1 (5
BSW3	50 k $\Omega$ pull-up res. I/O buffer, CMOS Schmitt in, CMOS 3-state out,	9.0	1 (11)	BE05	with 5K pull-up res.  18 mA I/O slew rate buffer (CMOS in / CMOS out)	1	1 (8
	$-5$ k $\Omega$ pull-up res. Number of internal cells required is shown in parer			BED5	18 mA I/O slew rate buffer (CMOS in / CMOS out with 50K pull-down res.		1 (8





Block Name	Description	Cells	Block Name	Description	Cells
	Interface Blocks (Cont.)			Function Blocks - Normal Power	
Slew F	ate Output Buffers (Cont.)		Inverte		
BEU5	18 mA I/O slew rate buffer (CMOS in / CMOS out) with 50K pull-up res.	1 (8)	F101 F102 F103	Inverter $(F/O = 17)$ Inverter $(F/O = 37)$ Inverter $(F/O = 60)$	1 2 3
BEW5 BE06	18 mA I/O slew rate buffer (CMOS in / CMOS out) with 5K pull-up res.  18 mA I/O slew rate buffer (TTL in / CMOS out)	1 (8) 1 (8)	F104 F108	Inverter $(F/O = 92)$ Inverter $(F/O = 160)$	4
BED6	18 mA I/O slew rate buffer (TTL in / CMOS out) with 50K pull-down res.	1 (8)	Buffer	,	
BEU6	18 mA I/O slew rate buffer (TTL in / CMOS out) with 50K pull-up res.	1 (8)	F111 F112	Non-inverting buffer (F/O = 17) Non-inverting buffer (F/O = 35)	2 3
BEW6	18 mA I/O slew rate buffer (TTL in / CMOS out) with 5K pull-up res.	1 (8)	F113	Non-inverting buffer (F/O = 54)	4
BFI5	18 mA Schmitt I/O slew rate buffer (CMOS in / CMOS out)	1 (11)	F114 F118	Non-inverting buffer ( $F/O = 74$ ) Non-inverting buffer ( $F/O = 180$ )	5 11
BFD5	18 mA Schmitt I/O slew rate buffer (CMOS in / CMOS out) with 50K pull-down res.	1 (11)	NOR C		
BFU5	18 mA Schmitt I/O slew rate buffer	1 (11)	F202 F203	2-input NOR 3-input NOR	2 3
BFW5	(CMOS in / CMOS out) with 50K pull-up res.  18 mA Schmitt I/O slew rate buffer	1 (11)	F204 F208	4-input NOR 8-input NOR	4 7
BFI6	(CMOS in / CMOS out) with 5K pull-up res.  18 mA Schmitt I/O slew rate buffer (TTL in / CMOS out)	1 (11)	F222 F223	2-input NOR, power 3-input NOR, power	4 6
BFD6	18 mA Schmitt I/O slew rate buffer (TTL in / CMOS out) with 50K pull-down res.	1 (11)	F224	4-input NOR, power	8
BFU6	18 mA Schmitt I/O slew rate buffer	1 (11)	OR Ga		
	(TTL in / CMOS out) with 50K pull-up res. 18 mA Schmitt I/O slew rate buffer	1 (11)	F212 F213 F214	2-input OR 3-input OR 4-input OR	2 3 3
	(TTL in / CMOS out) with 5K pull-up res.		F232	2-input OR, power	3
•	I Blocks	4 (04)	F233 F234	3-input OR, power 4-input OR, power	4 4
FIB1 FIB2 OSF1	Input buffer, CMOS in, high fanout for clock driver Input buffer, TTL in, high fanout for clock driver Feedback resistance for oscillator (low freq.)	1 (24) 1 (24) 1	NAND		
OSF2	Feedback resistance for oscillator (high freq.)	1	F302	2-input NAND	2
OSF3	Feedback resistance for oscillator with Enable (low freq.)	1	F303 F304	3-input NAND 4-input NAND	3 4
OSF4	Feedback resistance for oscillator with Enable (high freq.)	1	F305 F306	5-input NAND 6-input NAND	5 5
OSI1	Oscillator input buffer	1	F308	8-input NAND	6
OSI2	Oscillator input buffer with Enable Oscillator output buffer with feedback res. (low freq.)	1	F322	2-input NAND, power 3-input NAND, power	4
OSO2	Oscillator output buffer with feedback res. (high freq.)	1	F323 F324	4-input NAND, power	6 8
	Oscillator output buffer (low freq.) Oscillator output buffer (high freq.)	1 1	AND G	Gates	
OSO7	Oscillator output buffer with feedback res. & Enable	1	F312	2-input AND	2
OSO8	(low freq.) Oscillator output buffer with feedback res. & Enable	1	F313 F314	3-input AND 4-input AND	3 3
SHT1	(high freq.) Monostable multivibrator	1	F332 F333	2-input AND, power 3-input AND, power	3
	Oscillator pins must be used in combination. Some vali ations are:	d	F334	4-input AND, power	4
	SI1 + OSO1 Low Frequency		F421	2-wide 1-2-input AND-OR inverter	3
	SI1 + OSO3 + OSF1 Low Frequency SI1 + OSO2 High Frequency		F422 F423	3-wide 1-1-2-input AND-OR inverter 2-wide 1-3-input AND-OR inverter	4
0	SI2 + OSO7 Low Frequency with oscillator En	able	F424	2-wide 2-2-input AND-OR inverter	4
0	SI2 + OSO3 + OSF3  SI2 + OSO8  High Frequency with oscillator English Frequency with oscillator English Frequency with oscillator English	able	F425 F426 F429	3-wide 2-2-2-input AND-OR inverter 2-wide 3-3-input AND-OR inverter 4-wide 2-2-2-2-input AND-OR inverter	6 6 8
10		<del>.</del>	1 423	T-WIGE 2-2-2-IIIPUL AIND-ON IIIVEILEI	8



Block Name	Description	Cells	Block Name	Description (	Cells
	Function Blocks - Normal Power (Cont.)			Function Blocks - Normal Power (Cont.)	
OR-NA	ND Gates		Flip-Fl	ops	
F431 F432	2-wide 1-2-input OR-AND inverter 3-wide 1-1-2-input OR-AND inverter	3 4	F596 F611	Synchronous R-S F/F with Set-Reset D-F/F	11 8
F433 F434	2-wide 1-3-input OR-AND inverter 2-wide 2-2-input OR-AND inverter	4 4	F614 F617	D-F/F with Set-Reset D-F/F with Set-Reset low	10 10
F435	2-wide 2-3-input OR-AND inverter	5	F631	D-F/F C low	8
F436 F454	2-wide 3-3-input OR-AND inverter 4-wide 2-2-2-input OR-AND inverter	6 8	F637 F641 F647	D-F/F C low with Set-Reset low D-F/F, buffered D-F/F with Set-Reset low, buffered	10 8 10
Clock	Drivers		F661	D-F/F C low, buffered	8
F501	Clock driver	0	F667	D-F/F C low with Set-Reset low, buffered	10
F502	Dual clock driver	Ö	F714	Toggle F/F with Set-Reset	9
FCK1	Clock driver (F/O = 360)	40	F717	Toggle F/F with Set-Reset low	9
FCK2	Clock driver $(F/O = 720)$	80	F737	Toggle low F/F with Set-Reset low	9
FCK3	Clock driver $(F/O = 1080)$	120	F744 F747	Toggle F/F with Set-Reset, buffered Toggle F/F with Set-Reset low, buffered	9 9
FCK4	,	160 200	F747 F767	Toggle low F/F with Set-Reset low, buffered	9
FCK5	Clock driver (F/O = 1800)	200	F771	J-K F/F, buffered	10
EX-OF	l Gate		F774	J-K F/F with Set-Reset, buffered	12
F511	Exclusive-OR	4	F777 F781	J-K F/F with Set-Reset low, buffered J-K F/F C low, buffered	12 10
EX-NC	PR Gate		F787	J-K F/F C low with Set-Reset low, buffered	12
F512	Exclusive-NOR	4	F791 F792 F922	Toggle F/F with Set-Reset and Tog. Enable Toggle low F/F with Set-Reset and Tog. Enable low 4-bit D-F/F with Reset	12 12 33
Adder	s		F924	4-bit D-F/F	28
F521	1-bit full-adder	9	F924	4-Dit D-F/F	20
F523	4-bit binary full-adder	32	Count	ers	
Buffer F531	s 3-state buffer with Enable	5	F961 F962	4-bit synchronous binary counter with Reset low, buffered     4-bit synchronous binary up counter with Reset low	52 38
F532	3-state buffer with Enable low	5	Compa	arator	
			F985		32
Decod			F900	4-bit magnitude comparator	32
F561 F981	2-to-4 decoder 2-to-4 decoder with Enable low	10 13	Scan		
F982	3-to-8 decoder with Enable low	26	S000	Scan path D-F/F with Set-Reset	11
			S002	Scan path D-F/F	9
Shift F	Registers		S050 S052	Scan path D-F/F with Set-Reset, Hold Scan path D-F/F with Hold	14 12
F911	4-bit shift register with Reset	33	S100	Scan path J-K F/F with Set-Reset	14
F912 F913	4-bit serial/parallel shift register 4-bit parallel shift register with Reset low, Load	35 39	S100	Scan path J-K F/F	12
F914	4-bit shift register	28	S150 S152	Scan path J-K F/F with Set-Reset, Hold Scan path J-K F/F with Hold	17 15
Multip	lexers		S201	Scan path D-latch with Reset	12
F569	8-to-1 multiplexer	18	S202	Scan path D-latch	11
F570 F571	4-to-1 multiplexer 2-to-1 multiplexer	10 6	S301 S302	Scan path D-latch with Reset (ATG) Scan path D-latch (ATG)	8 7
F572	Quad 2-to-1 multiplexer	14	S999	Scan path 2-to-1 data selector	4
Latch	es		Delays	s	
F595	R-S latch	5	F130	Delay block (for monostable multivibrator)	8
F601 F602	D-latch D-latch with Reset	6 6	F131	Delay gate	6
F603	D-latch with Reset low	7	F132	Delay gate	1
F604	D-latch with G driver low	6			
F605	D-latch with G low, Reset low	7			
F901	4-bit D-latch	20			
F902	8-bit D-latch	38			





Block Name	Description	Cells	Block Name	Description	Cells
	Function Blocks – Low Power			Function Blocks - Low Power	
Multip	lexer				
L572	Quad 2-to-1 multiplexer	10		AND Gates	
Latche	·		L431 L432	2-wide 1-2-input OR-AND inverter 3-wide 1-1-2-input OR-AND inverter	2
L601	D-latch	3	L433 L434	2-wide 1-3-input OR-AND inverter 2-wide 2-2-input OR-AND inverter	2
L602	D-latch with Reset	4	L-10-	2-Wide 2-2-Input Off-AND Inverter	2
L603	D-latch with Reset low	4	1.405	Qualida Q Q inquit QD AND inventor	
L604	D-latch with G low driver	3	L435 L436	2-wide 2-3-input OR-AND inverter 2-wide 3-3-input OR-AND inverter	3
L605	D-latch with G low, R low	4	L454	4-wide 2-2-2-input OR-AND inverter	4
L901	4-bit latch	10		· · · · · · · · · · · · · · · · · · ·	·
L902	8-bit latch	18	EX-OF	ł Gate	
Invert	er		L511	EX-OR	3
L101	Inverter	1	EX-NC	PR Gate	
Buffer			L512	EX-NOR	3
L111	Non-inverting buffer	1	Decod	ers	
NOR C	Gates		L561	2-to-4 decoder	6
L202	2-input NOR	1	L981	2-to-4 decoder with Enable low	8
L203	3-input NOR	2	L982	3-to-8 decoder with Enable low	17
L204	4-input NOR	2	Flip Fl	ops	
00.0			L611	D-F/F	5
OR Ga			L614	D-F/F with Set-Reset	7
L212	2-input OR	2	L617	D-F/F with Set-Reset low	7
L213 L214	3-input OR 4-input OR	2 3	L631	D-F/F with C low	5
L214	4-input On	3	L637	D-F/F with R low, S low, C low	7
NAND	Gates		L714	Toggle-F/F with Set-Reset	7
L302	2-input NAND	1	L717	Toggle-F/F with Set-Reset low	7
L302	3-input NAND	2	L737	Toggle low F/F with Set-Reset low	7
L304	4-input NAND	2	L922	4-bit D-F/F with Reset	23
L305	5-input NAND	3	L924	4-bit D-F/F	18
L306	6-input NAND	3	Shift F	Registers	
AND C	Sates		L911	4-bit shift register with Reset	23
		2	L912	4-bit serial/parallel shift register	23
L312 L313	2-input AND 3-input AND	2 2	L913	4-bit parallel in shift register with Reset low	27
L314	4-input AND	3	L914	4-bit shift register	18
AND-N	NOR Gates				
L421	2-wide 1-2-input AND-OR inverter	2			
L422	3-wide 1-1-2-input AND-OR inverter	2			
L423 L424	2-wide 1-3-input AND-OR inverter 2-wide 2-2-input AND-OR inverter	2 2			
	·				
L425	3-wide 2-2-2-input AND OR inverter	3			
L426 L429	2-wide 3-3-input AND-OR inverter 4-wide 2-2-2-input AND-OR inverter	3 4			
L429	2-wide 4-4-input AND-OR inverter	4			
L462	3-wide 1-2-3-input AND-OR inverter	3			
	•				



Block	Description	Basic RAM	BIST	Cells	Block	Description	Basic RAM	BIST	Cells
	Memory Blocks					Memory Blocks			
High-S	peed Basic RAM Blocks - Hard Macı	os			High-S	peed Dual-Port RAM Blocks - Soft	Macros (C	Cont.)	
KD49	Single-port RAM (32 word x 4 bit)		_	574	RK8F	Dual-port RAM (256 word x 8 bit)	KE8F	RU8F	8887
KD8B	Single-port RAM (64 word x 8 bit)	_	_	1672	RK8H	Dual-port RAM (512 word x 8 bit)	KE8F		17501
KD8F	Single-port RAM (256 word x 8 bit)	_	_	5400	RKAB	Dual-port RAM (64 word x 10 bit)		RUAB	
KDAB	Single-port RAM (64 word x 10 bit)	_	_	1976	RKAD	Dual-port RAM (128 word x 10 bit)	KEAB	RUAD	5215
KDAF	Single-port RAM (256 word x 10 bit)	_	_	6600	RKAF	Dual-port RAM (256 word x 10 bit)		RUAF	
KE49	Dual-port RAM (32 word x 4 bit)	_	_	820	RKAH	Dual-port RAM (512 word x 10 bit)		RUAH	
KE87	Dual-port RAM (16 word x 8 bit)	_		520	RKC9	Dual-port RAM (32 word x 16 bit)	KE49		
KE8B	Dual-port RAM (64 word x 8 bit)	_	_	2128	RKCB	Dual-port RAM (64 word x 16 bit)	KE8B	RUCB	4609
KE8F	Dual-port RAM (256 word x 8 bit)	_		6000	RKCD	Dual-port RAM (128 word x 16 bit)	KE8B	RUCD	8927
KEAB	Dual-port RAM (64 word x 10 bit)	_	_	2432	RKCF	Dual-port RAM (256 word x 16 bit)	KE8F	RUCF	17491
KEAF	Dual-port RAM (256 word x 10 bit)	_	_	7200	RKEB	Dual-port RAM (64 word x 20 bit)	KEAB	RUEB	5249
	•				RKED	Dual-port RAM (128 word x 20 bit)	KEAB	RUED	10183
High-S	peed Single Port RAM Blocks - Soft	Macros			RKEF	Dual-port RAM (256 word x 20 bit)	KF49	RUH9	19968
RJ49	Single-port RAM (32 word x 4 bit)	KD49	RU49	778	RKH9	Dual-port RAM (32 word x 32 bit)		RUHB	
RJ4B	Single-port RAM (64 word x 4 bit)		RU4B	1381	RKHB	Dual-port RAM (64 word x 32 bit)		RUHD	
RJ4D	Single-port RAM (128 word x 4 bit)		RU4D	2556	RKHD	Dual-port RAM (128 word x 32 bit)		RUHD	
RJ4F	Single-port RAM (256 word x 4 bit)		RU4F	4908		,			
	•		RU89		RKKB	Dual-port RAM (64 word x 40 bit)		RUKB	
RJ89	Single-port RAM (32 word x 8 bit)		RU89	1384 1924	RKKD	Dual-port RAM (128 word x 40 bit)	KEAB	RUKD	20116
RJ8B	Single-port RAM (64 word x 8 bit)		RU8D	3632	Liimb D	amaity Cinala Bart BAM Blocks C	of Maara	_	
RJ8D RJ8F	Single-port RAM (128 word x 8 bit) Single-port RAM (256 word x 8 bit)		RU8F	7009	Hign-D	ensity Single-Port RAM Blocks - S	on macro	5	
ПООІ	Single-port ( Aim (230 word x 0 bit)	NDOD	11001	, 000	RB4D	Single-port RAM (128 word x 4 bit)	_	_	1170
RJ8H	Single-port RAM (512 word x 8 bit)		RU8H		RB4F	Single-port RAM (256 word x 4 bit)		_	2133
RJAB	Single-port RAM (64 word x 10 bit)		RUAB	2246	RB4H	Single-port RAM (512 word x 4 bit)	_	_	4030
RJAD	Single-port RAM (128 word x 10 bit)		RUAD	4262	RB4M	Single-port RAM (1K word x 4 bit)	_		7826
RJAF	Single-port RAM (256 word x 10 bit)	KDAB	RUAF	8247	RB4S	Single-port RAM (2K word x 4 bit)	_		15434
RJAH	Single-port RAM (512 word x 10 bit)	KDAB	RUAH	16249	RB4U	Single-port RAM (4K word x 4 bit)	_	_	30532
RJC9	Single-port RAM (32 word x 16 bit)		RUC9	2602	RB8D	Single-port RAM (128 word x 8 bit)	_	_	2137
RJCB	Single-port RAM (64 word x 16 bit)		RUCB	3666	RB8F	Single-port RAM (256 word x 8bit)	_	_	3622
RJCD	Single-port RAM (128 word x 16 bit)		RUCD	7062					
		L/D0D	51105	40700	RB8H	Single-port RAM 512 word x 8 bit)	_	_	6999
RJCF	Single-port RAM (256 word x 16 bit)		RUCF		RB8M	Single-port RAM (1K word x 8 bit)	_	_	11617
RJEB	Single-port RAM (64 word x 20 bit)		RUEB	4306	RB8S	Single-port RAM (2K word x 8 bit)	_		22958
RJED RJEF	Single-port RAM (128 word x 20 bit) Single-port RAM (256 word x 20 bit)		RUED		RBAF	Single-port RAM (256 word x 10 bit)		_	4439
NJEF	Single-port HAM (256 Word x 26 bit)	NUAU	HOLI	10203	RBAH	Single-port RAM (512 word x 10 bit)		_	8619
RJH9	Single-port RAM (32 word x 32 bit)	KD49	RUH9	5030	RBAM	Single-port RAM (1K word x 10 bit)	_	_	14369
RJHB	Single-port RAM (64 word x 32 bit)		RUHB	7143	RBAS	Single-port RAM (2K word x 8 bit)	_		28450
RJHD	Single-port RAM (128 word x 32 bit)		RUHD	13915	RBCD	Single-port RAM (128 word x 16 bit)	_		4077
RJKB	Single-port RAM (64 word x 40 bit)	KDAB	RUKB	8423	RBCF	Single-port RAM (256 word x 16 bit)		_	7032
RJKD	Single-port RAM (128 word x 40 bit)	KDAR	RUKD	16427	RBCH	Single-port RAM (236 word x 16 bit)		_	13764
HOND	Single port tixiw (120 word x 40 bit)	T(D/T)	, ITONE	10.2.	RBCM	,	_	_	22989
High-S	peed Dual Port RAM Blocks - Soft N	lacros			RBHD	Single-port RAM (128 word x 32 bit)			7949
•	•		DLIAG	1051					
RK49	Dual-port RAM (32 word x 4 bit)	KE49		1051	RBHF	Single-port RAM (256 word x 32 bit)		_	13844
RK4B	Dual-port RAM (64 word x 4 bit)	KE49		1910 3690	RBHH	Single-port RAM (512 word x 32 bit)		_	27289
RK4D	Dual-port RAM (128 word x 4 bit) Dual-port RAM (256 word x 4 bit)	KE49 KE49	_	3690 6944	RBKF	Single-port RAM (256 word x 40 bit)		_	17109
RK4F	Duai-poit maivi (200 word x 4 bit)	NE49	11041	0344	RBKH	Single-port RAM (512 word x 40 bit)		_	33769
RK87	Dual-port RAM (16 word x 8 bit)	KE87							
RK89	Dual-port RAM (32 word x 8 bit)	KE49		1904					
RK8B	Dual-port RAM (64 word x 8 bit)		RU8B	2413					
	Dual-port RAM (128 word x 8 bit)	VEOD	RU8D	4587					





Block	Description	Basic RAM	BIST	Cells	Block	Description	Basic RAM	BIST	Cells	
	Memory Blocks (6	Cont.)		Memory Blocks (Cont.)						
ком в	locks				RAM T	est (BIST)				
J14D J14F J14H	128 word x 4 bit ROM 256 word x 4 bit ROM 512 word x 4 bit ROM	_	_	720 1040 1512	RU49 RU4B RU4D	32 word x 4 bit 64 word x 4 bit 128 word x 4 bit	_			
J14M	1K word x 4 bit ROM	_	_	2408	RU4F	256 word x 4 bit		_		
J14S J14U J18D J18F	2K word x 4 bit ROM 4K word x 4 bit ROM 128 word x 8 bit ROM 256 word x 8 bit ROM	_ _ _		3960 6776 1040 1456	RU87 RU89 RU8B RU8D	16 word x 8 bit 32 word x 8 bit 64 word x 8 bit 128 word x 8 bit	_ _ _ _	_ _ _		
J18H J18M J18S J18U	512 word x 8 bit ROM 1K word x 8 bit ROM 2K word x 8 bit ROM 4K word x 8 bit ROM	_ _ 	_ _ _ _	2352 3784 6600 11704	RU8F RU8H RUAB RUAD	256 word x 8 bit 512 word x 8 bit 64 word x 10 bit 128 word x 10 bit	_ _ _	_ _ _ _		
J18W J1CD J1CF J1CH	4K word x 8 bit ROM 128 word x 16 bit ROM 256 word x 16 bit ROM 512 word x 16 bit ROM	_ _ _	_ _ _	21584 1456 2352 3696	RUAF RUAH RUC9 RUCB	256 word x 10 bit 512 word x 10 bit 32 word x 16 bit 64 word x 16 bit	_ _ _	_ _ _		
J1CM J1CS J1CU J1HF	1K word x 16 bit ROM 2K word x 16 bit ROM 4K word x 16 bit ROM 256 word x 32 bit ROM	_ _ _	<del>-</del> -	6512 11400 21280 3696	RUCD RUCF RUEB RUED	128 word x 16 bit 256 word x 16 bit 64 word x 20 bit 128 word x 20 bit	_ _ _	_ _ _		
J1HH J1HM J1HS	512 word x 32 bit ROM 1K word x 32 bit ROM 2K word x 32 bit ROM	_ _ _	<u>-</u> -	6512 11248 21128	RUEF RUH9 RUHB RUHD	256 word x 20 bit 32 word x 32 bit 64 word x 32 bit 128 word x 32 bit	_ _ _ _	_ _ _ _		
					RUKB RUKD	64 word x 40 bit 128 word x 40 bit	_ _	_		



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